



IPB64N25S3-20

OptiMOS[®]-T Power-Transistor

Features

- N-channel - Enhancement mode
- AEC qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green Product (RoHS compliant)
- 100% Avalanche tested

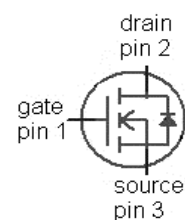
Product Summary

V_{DS}	250	V
$R_{DS(on),max}$	20	mΩ
I_D	64	A

PG-TO263-3-2



Type	Package	Marking
IPB64N25S3-20	PG-TO263-3-2	3PN2520

Maximum ratings, at $T_j=25\text{ °C}$, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I_D	$T_C=25\text{ °C}$, $V_{GS}=10\text{ V}$	64	A
		$T_C=100\text{ °C}$, $V_{GS}=10\text{ V}^{1)}$	46	
Pulsed drain current ¹⁾	$I_{D,pulse}$	$T_C=25\text{ °C}$	256	
Avalanche energy, single pulse ¹⁾	E_{AS}	$I_D=27\text{ A}$	270	mJ
Avalanche current, single pulse	I_{AS}	-	27	A
Reverse diode dv/dt	dv/dt		6	kV/μs
Gate source voltage	V_{GS}	-	±20	V
Power dissipation	P_{tot}	$T_C=25\text{ °C}$	300	W
Operating and storage temperature	T_j , T_{stg}	-	-55 ... +175	°C
IEC climatic category; DIN IEC 68-1	-	-	55/175/56	

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

Thermal characteristics^{1), 3)}

Thermal resistance, junction - case	R_{thJC}	-	-	-	0.5	K/W
Thermal resistance, junction - ambient, leaded	R_{thJA}	-	-	-	62	
SMD version, device on PCB	R_{thJA}	minimal footprint	-	-	62	
		6 cm ² cooling area ²⁾	-	-	40	

Electrical characteristics, at $T_j=25^\circ\text{C}$, unless otherwise specified
Static characteristics

Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=1mA$	250	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=270\mu A$	2.0	3.0	4.0	
Zero gate voltage drain current	I_{DSS}	$V_{DS}=250V, V_{GS}=0V$	-	0.1	1	μA
		$V_{DS}=250V, V_{GS}=0V, T_j=125^\circ\text{C}^{2)}$	-	10	100	
Gate-source leakage current	I_{GSS}	$V_{GS}=20V, V_{DS}=0V$	-	1	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=64A$	-	17.5	20	m Ω



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Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

Dynamic characteristics¹⁾

Input capacitance	C_{iss}	$V_{GS}=0V, V_{DS}=25V,$ $f=1MHz$	-	5240	7000	pF
Output capacitance	C_{oss}		-	2900	3900	
Reverse transfer capacitance	C_{rss}		-	85	170	
Turn-on delay time	$t_{d(on)}$	$V_{DD}=100V, V_{GS}=10V,$ $I_D=25A, R_G=1.6\Omega$	-	18	-	ns
Rise time	t_r		-	20	-	
Turn-off delay time	$t_{d(off)}$		-	45	-	
Fall time	t_f		-	12	-	

Gate Charge Characteristics¹⁾

Gate to source charge	Q_{gs}	$V_{DD}=200V, I_D=64A,$ $V_{GS}=0 \text{ to } 10V$	-	24	31	nC
Gate to drain charge	Q_{gd}		-	11	22	
Gate charge total	Q_g		-	67	89	
Gate plateau voltage	$V_{plateau}$		-	4.8	-	V

Reverse Diode

Diode continuous forward current ¹⁾	I_S	$T_C=25^\circ C$	-	-	64	A
Diode pulse current ¹⁾	$I_{S,pulse}$		-	-	256	
Diode forward voltage	V_{SD}	$V_{GS}=0V, I_F=64A,$ $T_j=25^\circ C$	-	1	1.2	V
Reverse recovery time ¹⁾	t_{rr}	$V_R=125V, I_F=50A,$ $di_F/dt=100A/\mu s$	-	174	-	ns
Reverse recovery charge ¹⁾	Q_{rr}		-	1095	-	nC

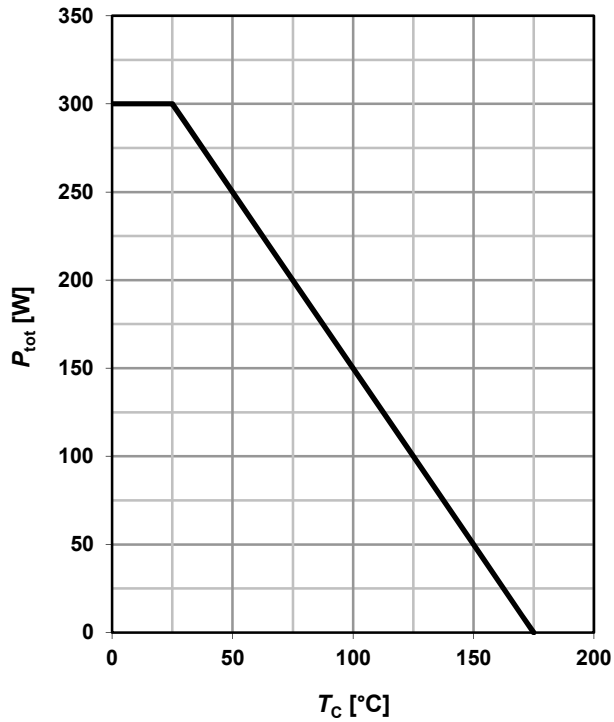
¹⁾ Defined by design. Not subject to production test.

²⁾ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.

³⁾ Devices thermal performance determined according to EIA JESD 51-14
"Transient Dual Interface Test Method For The Measurement Of The Thermal Resistance"

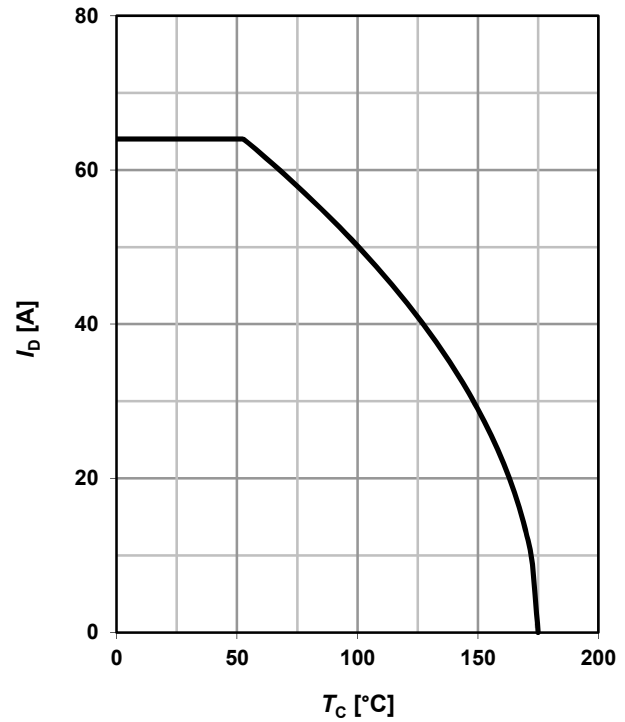
1 Power dissipation

$$P_{\text{tot}} = f(T_C); V_{\text{GS}} \geq 6 \text{ V}$$



2 Drain current

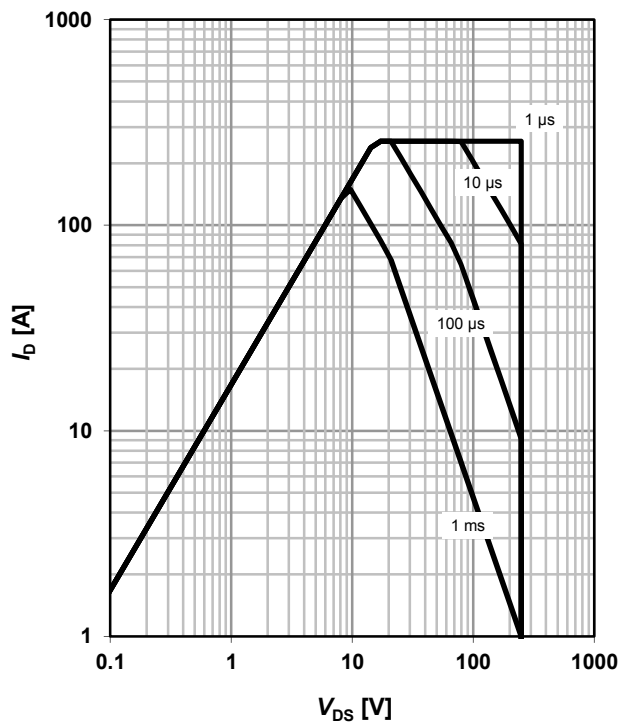
$$I_D = f(T_C); V_{\text{GS}} \geq 6 \text{ V}; \text{SMD}$$



3 Safe operating area

$$I_D = f(V_{\text{DS}}); T_C = 25 \text{ °C}; D = 0; \text{SMD}$$

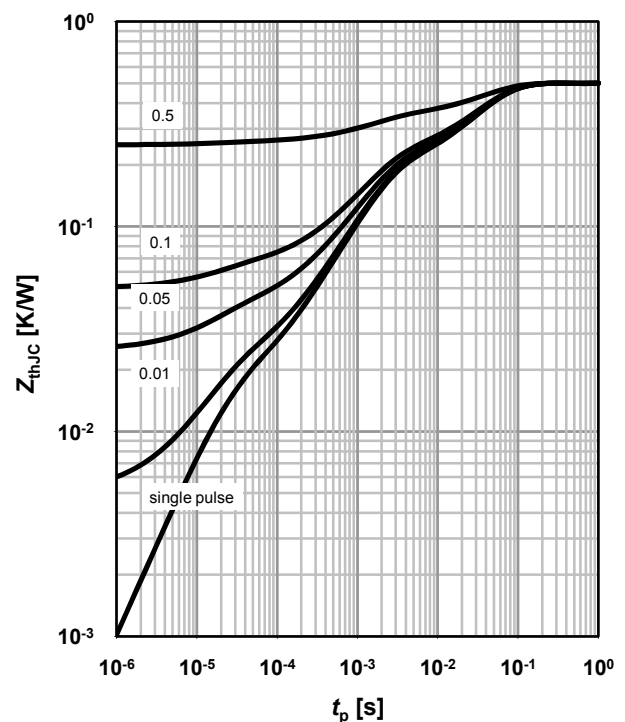
parameter: t_p



4 Max. transient thermal impedance

$$Z_{\text{thJC}} = f(t_p)$$

parameter: $D = t_p/T$

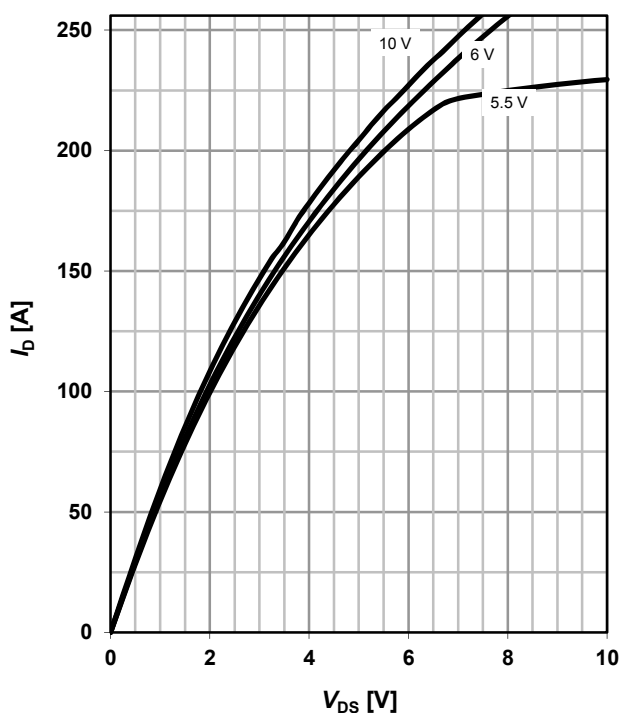




5 Typ. output characteristics

$I_D = f(V_{DS}); T_j = 25^\circ\text{C}; \text{SMD}$

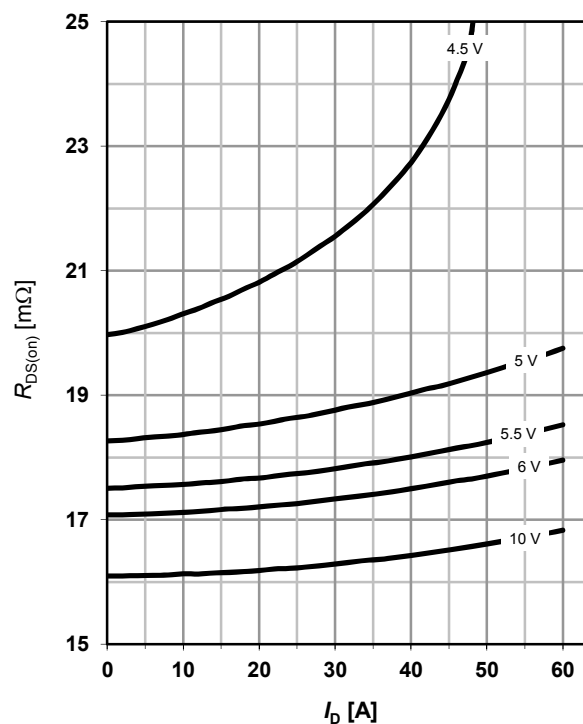
parameter: V_{GS}



6 Typ. drain-source on-state resistance

$R_{DS(on)} = f(I_D); T_j = 25^\circ\text{C}; \text{SMD}$

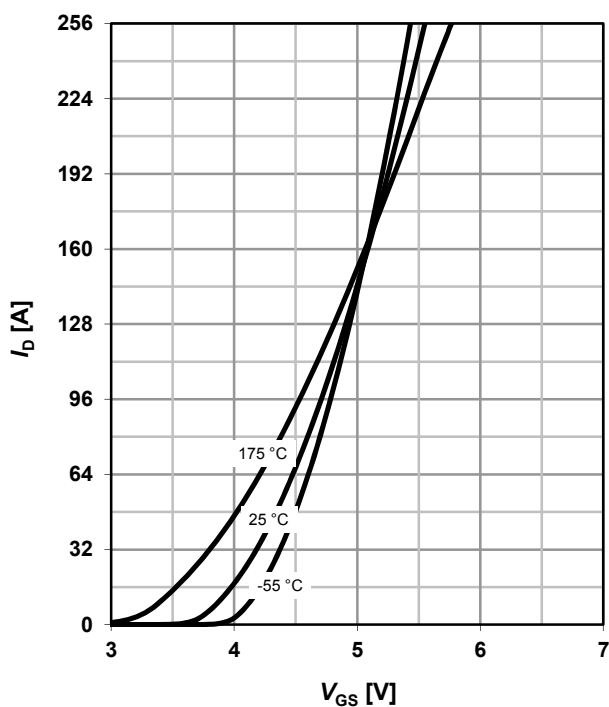
parameter: V_{GS}



7 Typ. transfer characteristics

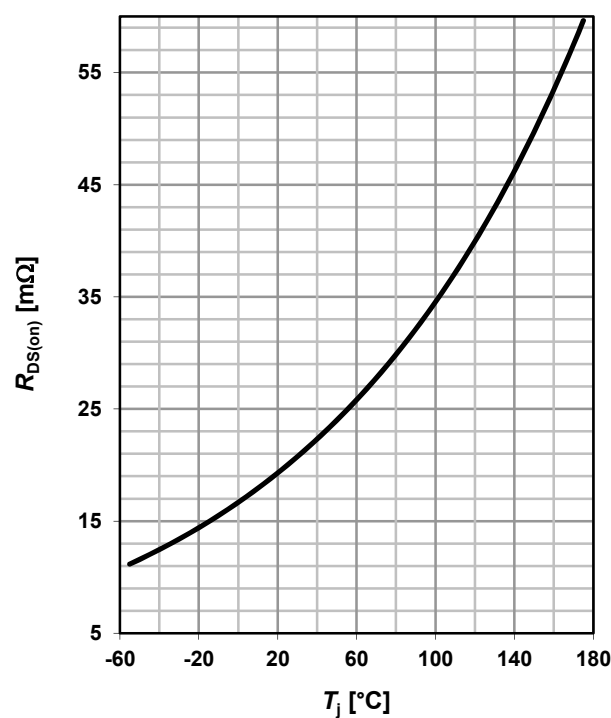
$I_D = f(V_{GS}); V_{DS} = 6\text{ V}$

parameter: T_j



8 Typ. drain-source on-state resistance

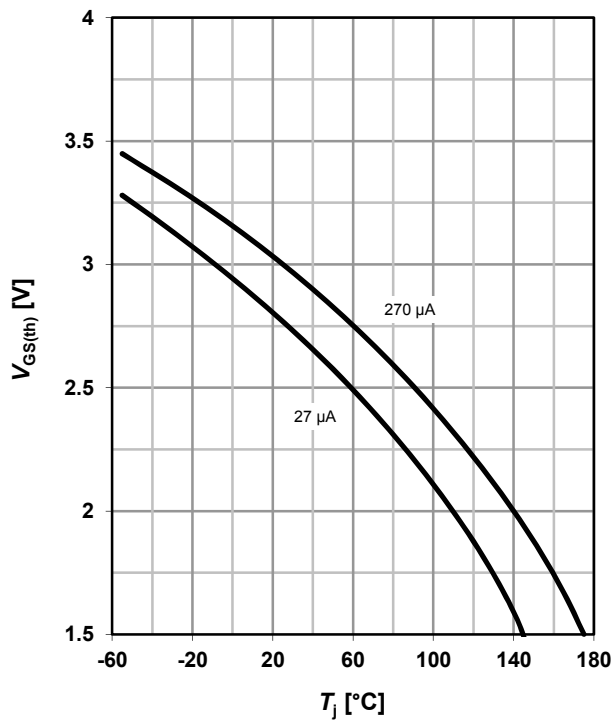
$R_{DS(on)} = f(T_j); I_D = 64\text{ A}; V_{GS} = 10\text{ V}; \text{SMD}$



9 Typ. gate threshold voltage

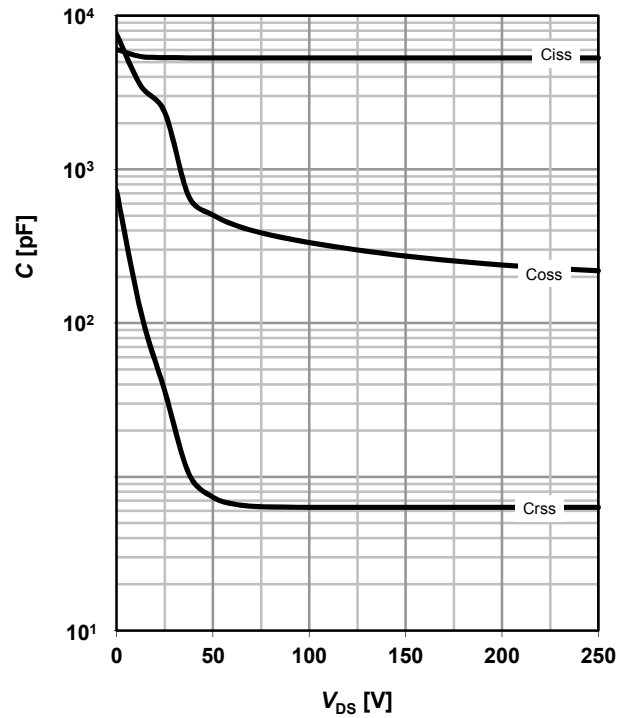
$$V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$$

parameter: I_D



10 Typ. capacitances

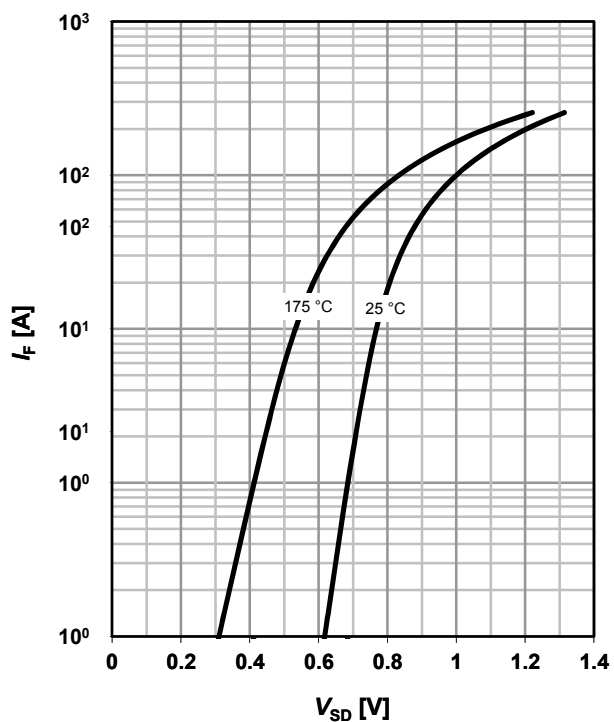
$$C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$$



11 Typical forward diode characteristics

$$I_F = f(V_{SD})$$

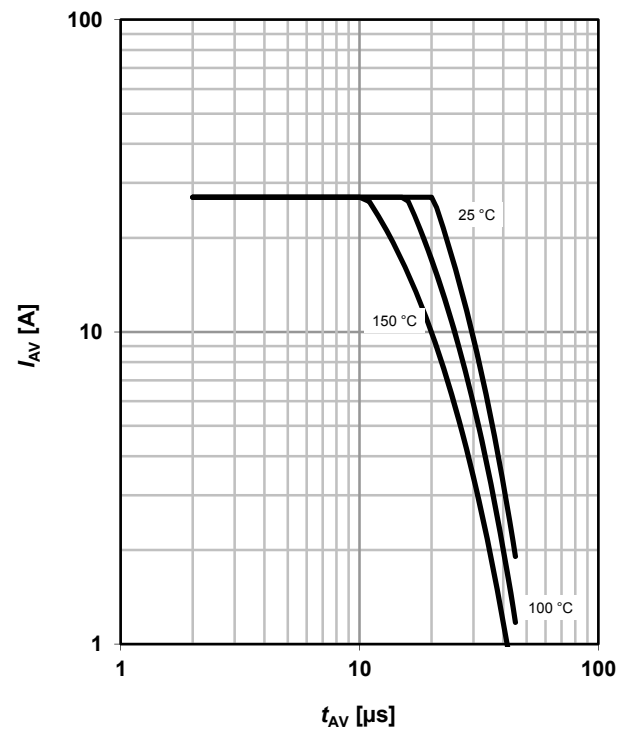
parameter: T_j



12 Avalanche characteristics

$$I_{AS} = f(t_{AV})$$

parameter: $T_{j(start)}$



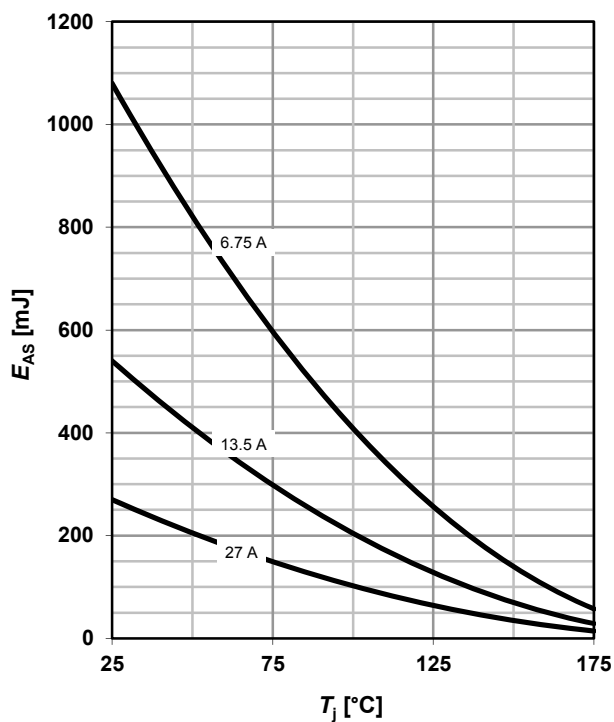


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13 Avalanche energy

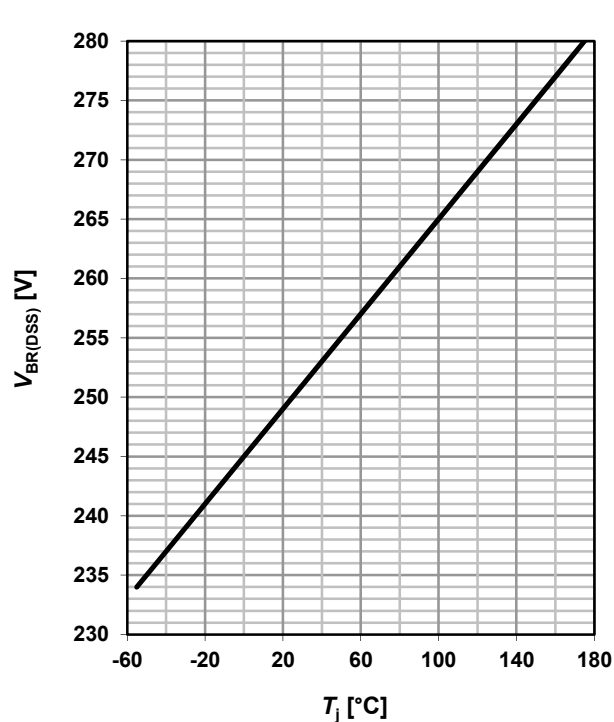
$$E_{AS} = f(T_j)$$

parameter: I_D



14 Drain-source breakdown voltage

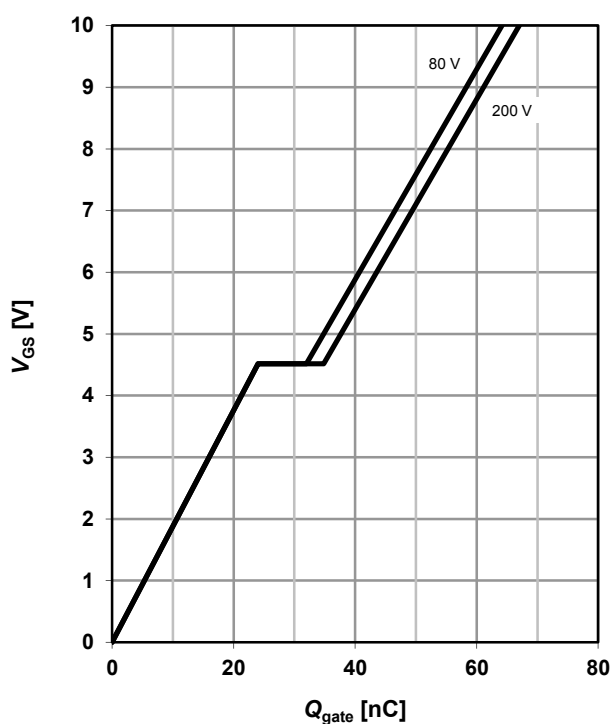
$$V_{BR(DSS)} = f(T_j); I_D = 270 \mu A$$



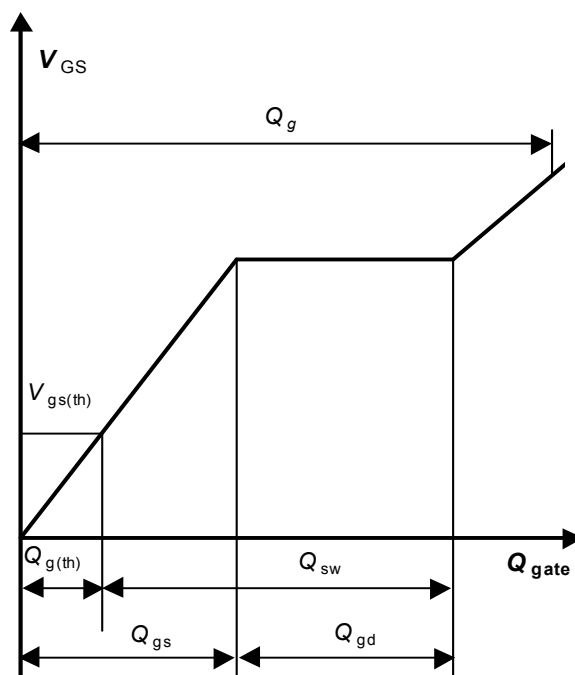
15 Typ. gate charge

$$V_{GS} = f(Q_{gate}); I_D = 64 \text{ A pulsed}$$

parameter: V_{DD}



16 Gate charge waveforms



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Revision History

Version	Date	Changes
Revision 1.0	2012-10-18	Final Data Sheet
Revision 1.1	2014-09-12	Through-hole parts removed